

650V N-Channel Enhancement Mode MOSFET

Description

The AP4N65D/Y is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

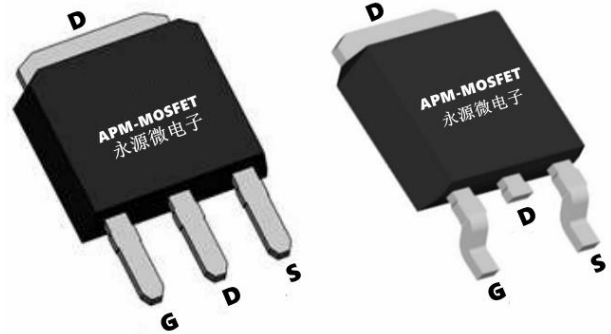
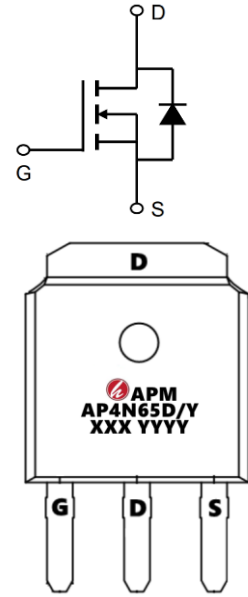
$V_{DS} = 650V$ $I_D = 4A$

$R_{DS(ON)} < 2.4\Omega$ @ $V_{GS}=10V$ (Type: 2.0 Ω)

Application

Uninterruptible Power Supply(UPS)

LED



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4N65D	TO-252-3L	AP4N65D XXX YYYY	2500
AP4N65Y	TO-251S-3L	AP4N65Y XXX YYYY	4000

Absolute Maximum Ratings ($T_c=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage ($V_{GS} = 0V$)	650	V
I_D	Continuous Drain Current	4	A
I_{DM}	Pulsed Drain Current (note1)	25	A
V_{GS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note2)	80	mJ
I_{AR}	Avalanche Current (note1)	16	A
E_{AR}	Repetitive Avalanche Energy note1)	4.5	mJ
P_D	Power Dissipation ($T_c = 25^{\circ}C$)	35	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^{\circ}C$
R_{thJC}	Thermal Resistance, Junction-to-Case	5.1	$^{\circ}C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62.5	$^{\circ}C/W$



650V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	650			V
ΔBV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, Referenced to 25°C		0.64		V/°C
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V			1	μA
		V _{DS} = 520 V, TC = 125°C			10	μA
IGSSF	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
IGSSR	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
VGS(TH)	Gate Threshold voltage	V _{DS} =V _{GS} , I _D =250 uA	2.0		4.0	V
RDS(On)	Drain-Source on-state resistance	V _{GS} =10 V, I _D =2A, T _J = 25°C		2.0	2.4	Ω
gFS	Forward Transconductance	V _{DS} =40 V, I _D =2 A (Note 4)		3.8		S
C _{iss}	Input capacitance	V _{DS} =25V, V _{GS} =0 V, f=1.0 MHz		415		pF
C _{oss}	Output capacitance			58		pF
C _{rss}	Reverse transfer capacitance			1.4		pF
td(on)	Turn On Delay Time	V _{DD} =325V, I _D =4A, R _G =25Ω (Note 4, 5)		7		ns
t _r	Rising Time			22		ns
td(off)	Turn Off Delay Time			15		ns
t _f	Fall Time			23		ns
Q _g	Total Gate Charge	V _{DS} = 520 V, I _D = 4 A, V _{GS} = 10 V (Note 4, 5)		13		nC
Q _{gs}	Gate-Source Charge			4.9		nC
Q _{gd}	Gate-Drain Charge			2.3		nC
ISM	Maximum Pulsed Drain-Source Diode Forward Current				16	A
V _{SD}	Diode Forward Voltage	V _{GS} = 0 V, I _S = 4 A			1.2	V
trr	Reverse Recovery Time	V _{GS} = 0 V, I _S = 4 A, dI _F / dt = 100 A/μs (Note 4)		378		ns
Q _{rr}	Reverse Recovery Charge			1.35		μC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . L=4.1Mh IAS=18A, VDD=50V, RG=25Ω, Starting T_J = 25 °C
- 3、The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

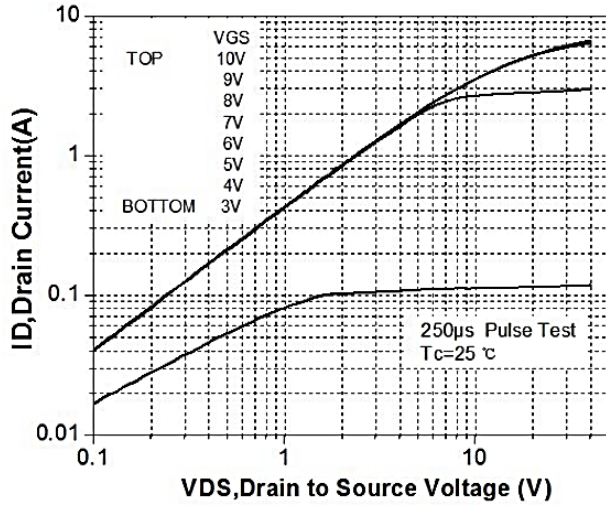


Figure 1. On-Region Characteristics

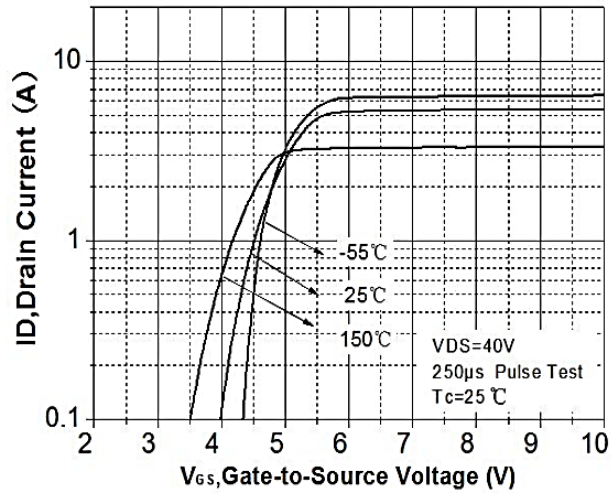


Figure 2. Transfer Characteristics

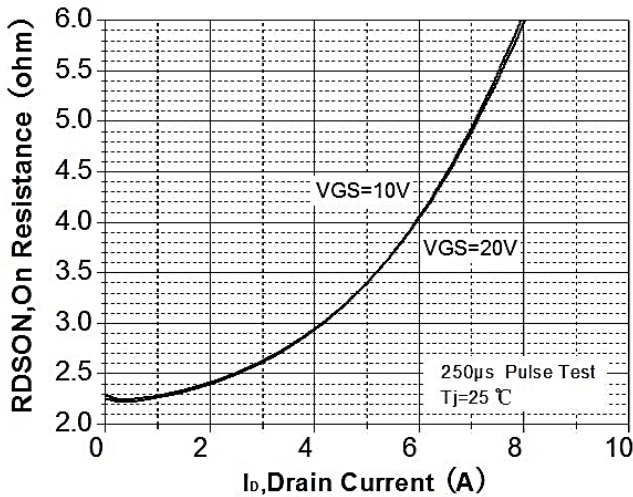


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

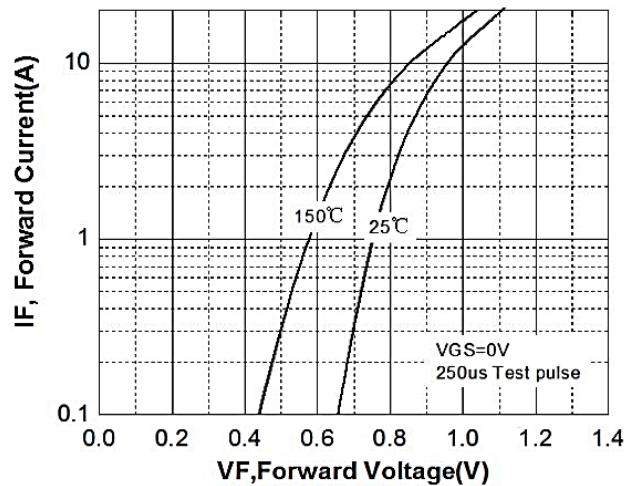


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

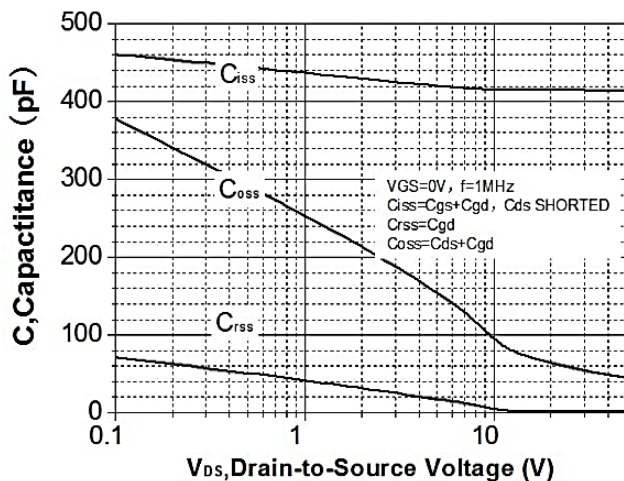


Figure 5. Capacitance Characteristics

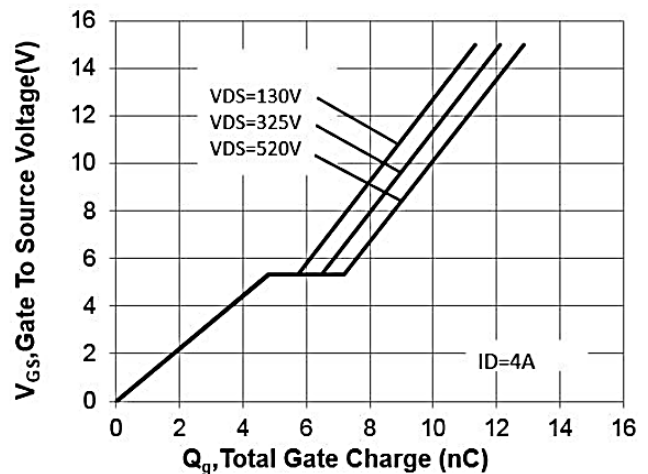


Figure 6. Gate Charge Characteristics

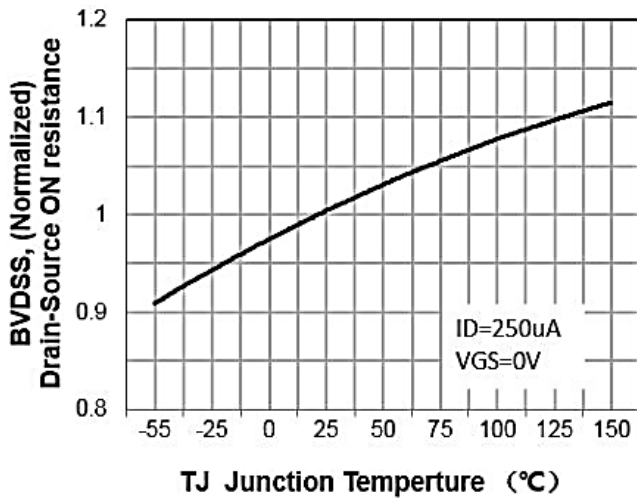


Figure 7. Breakdown Voltage Variation vs Temperature

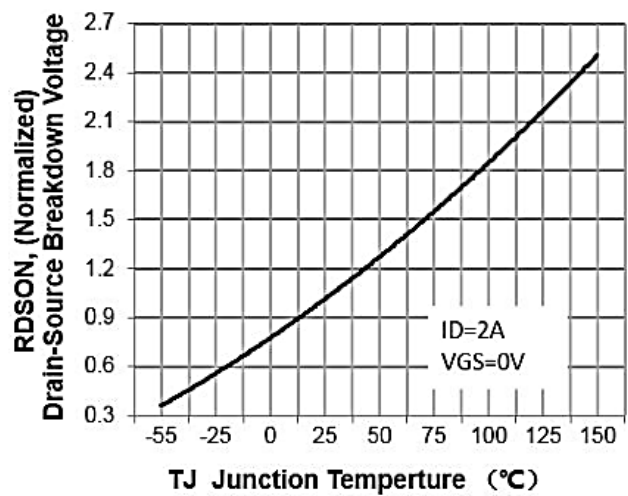


Figure 8. On-Resistance Variation vs Temperature

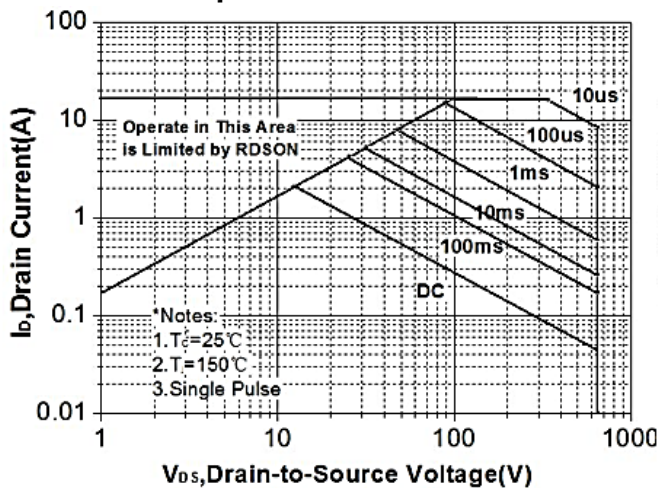


Figure 9. Maximum Safe Operating Area

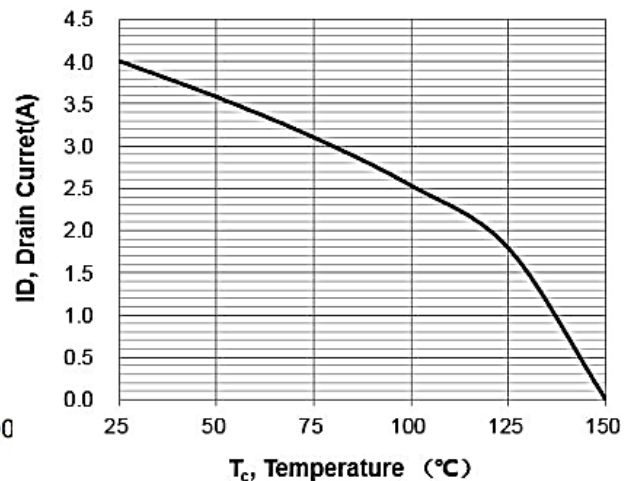


Figure 10. Maximum Drain Current vs Case Temperature

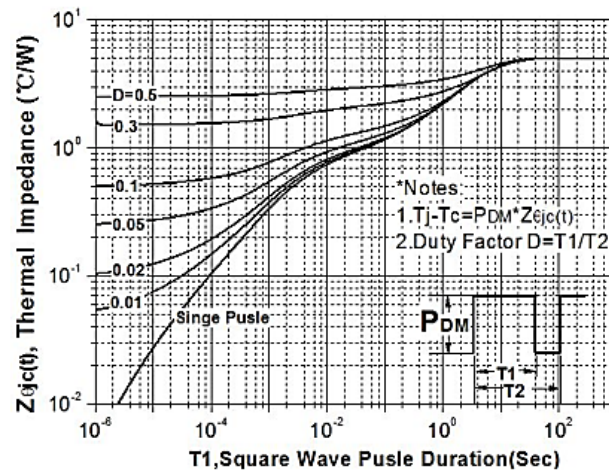
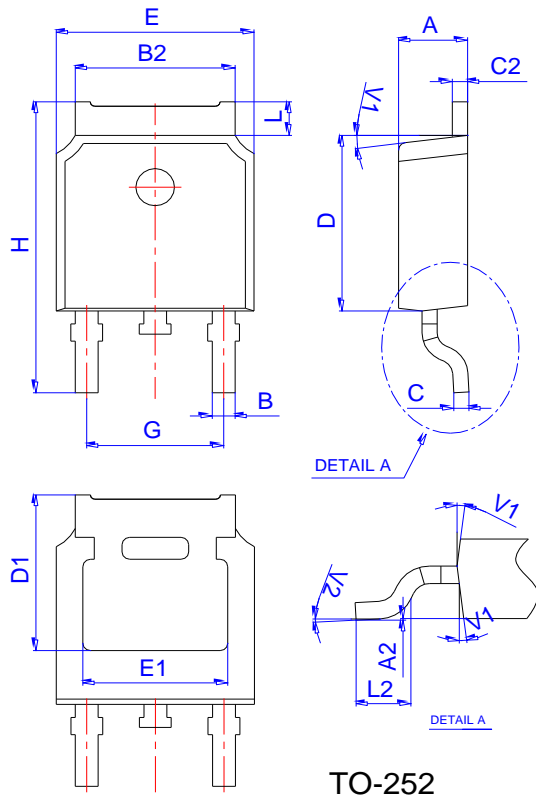


Figure 11. Transient Thermal Response Curve

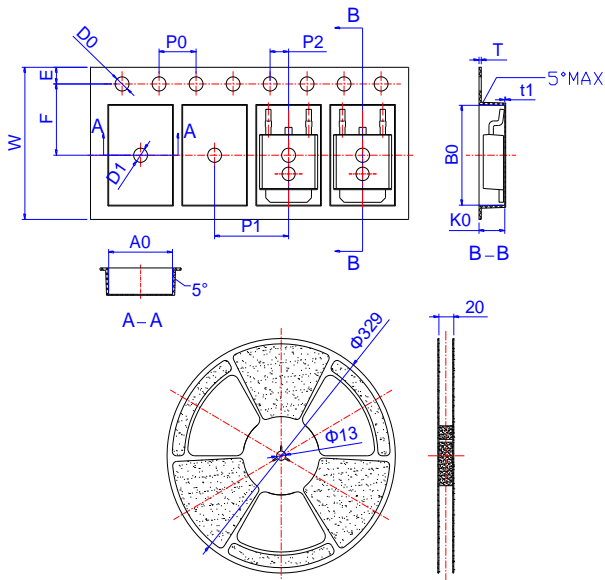
650V N-Channel Enhancement Mode MOSFET

Package Mechanical Data:TO-252-3L



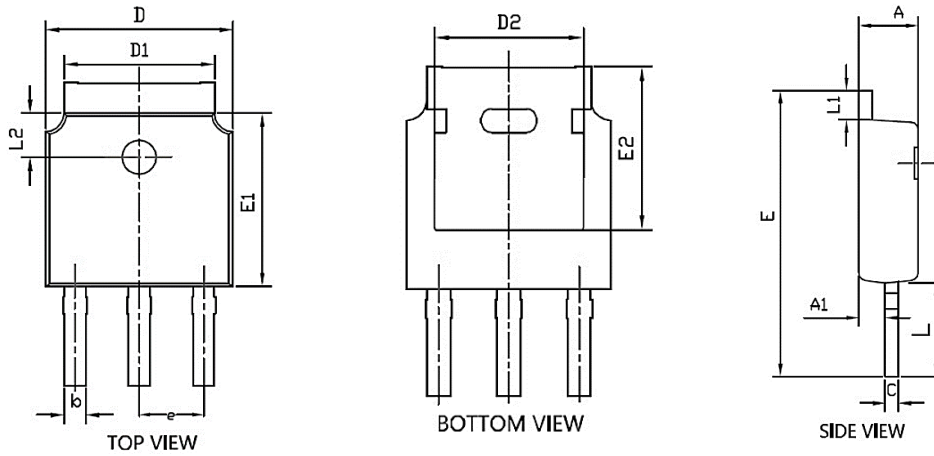
Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

Package Mechanical Data-TO-251S-3L



Symbol	Common		
	mm		
	Mim	Nom	Max
A	2.2	2.3	2.4
A1	0.9	1.0	1.1
b	0.66	0.76	0.86
C	0.46	0.52	0.58
D	6.50	6.6	6.7
D1	5.15	5.3	5.45
D2	4.6	4.8	4.95
E	10.4	----	11.5
E1	6.0	6.1	6.2
E2	5.400REF		
e	2.286BSC		
L	3.5	4.0	4.3
L1	0.9	---	1.27
L2	1.4	---	1.9

650V N-Channel Enhancement Mode MOSFET**Attention**

1, Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.

2, APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.

3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

5, In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.

7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the APM Microelectronics product that you intend to use.



Edition	Date	Change
Rve1.0	2020/1/31	Initial release
Rve1.1	2022/10/22	Format change

Copyright Attribution“APM-Microelectronice”